Q: How do you customize the AutoTest logfile format?

Customizing The AutoTest Log File

Data logging of AutoTest results can be customized to help meet a user's desired format. To enable this feature, first you must activate the keyword *CustomAutoTestLogTemplate* in file SpScript.txt by removing the leading semicolon from the line containing this keyword (or by typing in the keyword on a blank line if it is not already present). The file SpScript.txt is located in c:\ETSusb. The keyword must be followed by the name of the file that contains log file format. Here is an example of this SpScript.txt line:

CustomAutoTestLogTemplate c:\ETSusb\ATTempl.txt

In this example, "ATTempl.txt" is the template file that the feature is using for parameters. An example of the contents of ATTempl.txt appears in this document. If the file is not present, then standard data logging will be used. The Custom Log File feature can be used only in the "single site mode" at this time.

Once the SpScript.txt file has been edited to enable the feature, save it and restart the ETS2k software (you must close ETS2k software if it is already running). This will automatically enable the feature.

The Log File Format appears below in its basic form:

```
#section_name
<field_name>
.
.
#end
```

The following section names are available:

```
#DEFINE   - defines PASS and FAIL character strings
#HEADER ó this section contains strings that will appear in the log file header
#DETAILS ó this section contains the string that will be saved in the log file for every
            executed test
```

Each section can contain special keywords (always in brackets < > - except for the DEFINE section), which will add information to the log file. Keywords that cannot be

recognized will be ignored. Strings that are not in brackets will simply be copied into the log file.

The following keywords are allowed for the specified sections:

#DEFINE section
(If there are no defined strings ó default strings will be used (õPassedö and õFailedö))
Passed   - string used to indicate õpassedö test
Failed   - string used to indicate õfailedö test

#HEADER section
<DATE>   - current date
<TIME>   - current time
<SERNR>   - serial number   (from More Info window)
<OPERATOR>   - operator name   (from More Info window)
<ENVIRONMENT >   - environment   (from More Info window)
<NOTES>   - notes   (from More Info window)
<DEVICENAME>   - device name
<DEVICENR>   - device number
<LOTID>   - lot ID
<WAFERID>   - wafer ID
<XYPOS>   - die position

#DETAILS section
<TESTNR>   - test number
<TESTNAME>   - test name
<LOWLIMIT>   - low limit
<HIGHLIMIT>   - high limit
<RESULT>   - test result
<PASSFAIL>   - õpassedö/öfailedö string

A basic example of a template file (ATTempl.txt) appears on the next page.

```
#DEFINE
Passed p
Failed f
#END

#HEADER
Auto Test Log File '<DEVICENAME>'
Date <DATE>    <TIME>
Operator <OPERATOR>
Environment <ENVIRONMENT>
Device # <DEVICENR>
Serial Number    <SERNR>
#END

#DETAILS
Test <TESTNR>, <TESTNAME>, <LOWLIMIT>, <HIGHLIMIT>, <RESULT>, <PF>
#END
```

Basic example of template file "ATTempl.txt"

The string to the left of the bracketed keyword is the label defined by the user that will appear in the AutoTest log file, and it will be followed by data entered at the time of test execution (represented by the keyword). Only one line appears for each test. However, if there is a failure, the first failed pin only appears on the line; other failed pins must be identified by standard logging or by Failure Analysis. The Auto Test Log file for the above example will then look like the example below.

```
Auto Test Log File 'PostBake'
Date 7/12/2004   5:35:03 PM
Operator  Peter
Environment  HOT
Device # 1
Serial Number   0098

Test 2,SupplyCurr, 1.000  mA, 250.000  mA,0.000 nA,p
Test 3,RecXmit,  ,  , ,p
Test 4,Den,  ,  , ,p
Test 6,PROMA,  ,  , ,p
Test 7,PROMB,  ,  , ,p
Test 10,IILStd, -500.000  uA,  ,  0.000 nA,p
Test 11,IILOv,  , 10.000  uA,     0.000 nA,p
Test 12,IILGac, -300.000  uA, -20.000  uA,        0.000 nA,f
Test 13,IILdiff, -20.000  uA, 20.000  uA, 0.000 nA,p
Test 14,IIHstd, -300.000  uA, 10.000  uA,          0.000 nA,p
Test 15,IIHOv, 40.000  uA, 400.000  uA,0.000 nA,f
Test 16,IIHdiff, 50.000  uA, 220.000  uA,          0.000 nA,f
Test 17,VOLp, 0.350  V, 1.400  V,        0.000 nV,f
Test 18,VOHp, 4.100  V, 5.040  V,        0.000 nV,f
Test 19,VOHen, 4.800  V, 5.500  V,       0.000 nV,f
Test 21,DynCurr, -1.000  mA, 150.000  mA,0.000 nA,p
Test 26,GDel, 30.0ns, 100.0ns,82.5ns,p

   $$$$$$$$    SUMMARY REPORT    $$$$$$$$

Total Devices: 1;  Passed: 0;  Failed: 1;   Yield = 0%
```

Custom AutoTest Logfile with "More Information"

Also see Q'nApp #E47 on the "More..." button and Q'nApp #E57 on AutoTest Timestamp.